

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|---|--|------------------|---------|------------------|
| S1 | 3 | ("20030022397") or ("5947053") or ("6394023").PN. | US-PGPUB; USPAT | OR | OFF | 2004/12/20 10:30 |
| S2 | 1940 | (116/208,212,206,200).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/20 10:31 |
| S9 | 13 | wafer and S2 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/20 10:33 |
| S11 | 4 | wafer and etching and S2 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/20 10:33 |
| S16 | 414 | (216/59).CCLS. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:28 |
| S17 | 691 | (156/345.24,345.25,345.26,345.27, 345.28).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:22 |
| S18 | 0 | wear adj indicator and semi adj conductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:29 |
| S19 | 12 | wear adj indicator and wafer | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:29 |
| S20 | 17 | wear adj indicator and semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:34 |

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|-----|------|--|---|----|-----|------------------|
| S21 | 100 | wear adj indicator and "116"/\$.ccls. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:34 |
| S22 | 847 | (438/6-9).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:42 |
| S23 | 1457 | (438/6-10).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:43 |
| S24 | 840 | (438/10-12).CCLS. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/12/22 14:47 |
| S25 | 21 | ("2285929" "3362376" "3814160" "3987822" "4074742" "4102363" "4119123" "4283455" "4690177"). PN. OR ("4982767").URPN. | US-PGPUB; USPAT; USOCR | OR | OFF | 2004/12/22 14:52 |